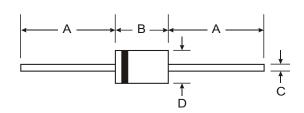


# PR2001 - PR2005

### 2.0A FAST RECOVERY RECTIFIER

#### **Features**

- Diffused Junction
- Fast Switching for High Efficiency
- High Current Capability and Low Forward Voltage Drop
- Surge Overload Rating to 50A Peak
- Low Reverse Leakage Current
- Plastic Material: UL Flammability Classification Rating 94V-0



#### **Mechanical Data**

Case: Molded Plastic

 Terminals: Plated Leads Solderable per MIL-STD-202, Method 208

Polarity: Cathode BandMarking: Type Number

• Weight: 0.4 grams (approx.)

DO-15							
Dim	Min	Max					
Α	25.40	_					
В	5.50	7.62					
С	0.686	0.889					
D	2.60	3.6					
All Dimensions in mm							

## Maximum Ratings and Electrical Characteristics @ TA = 25°C unless otherwise specified

Single phase, half wave, 60Hz, resistive or inductive load. For capacitive load, derate current by 20%.

Characteristic	S	Symbol	PR 2001	PR 2002	PR 2003	PR 2004	PR 2005	Unit
Peak Repetitive Reverse Voltage Working Peak Reverse Voltage DC Blocking Voltage		V <sub>RRM</sub> V <sub>RWM</sub> V <sub>R</sub>	50	100	200	400	600	V
RMS Reverse Voltage	\	V <sub>R(RMS)</sub>	35	70	140	280	420	V
Average Rectified Output Current (Note 1) @ T,	A = 50°C	lo	•		2.0			А
Non-Repetitive Peak Forward Surge Current 8.3ms Single half sine-wave Superimposed on Ra (JEDEC Method)	ited Load	I <sub>FSM</sub>			50			А
Forward Voltage @ I	F = 2.0A	$V_{FM}$	1.2					V
	= 25°C = 100°C	I <sub>RM</sub>	5.0 100					μА
Reverse Recovery Time (Note 3)		t <sub>rr</sub>		15	50		250	ns
Typical Junction Capacitance (Note 2)		Cj		3	5		15	pF
Typical Thermal Resistance Junction to Ambient		$R_{\theta JA}$	50					K/W
Operating and Storage Temperature Range		T <sub>j,</sub> T <sub>STG</sub>	-65 to +150					°C

es: 1. Valid provided that leads are maintained at ambient temperature at a distance of 9.5mm from the case.

- 2. Measured at 1.0MHz and applied reverse voltage of 4.0 V DC.
- 3. Measured with  $I_F$  = 0.5A,  $I_R$  = 1.0A,  $I_{rr}$  = 0.25A. See figure 5.



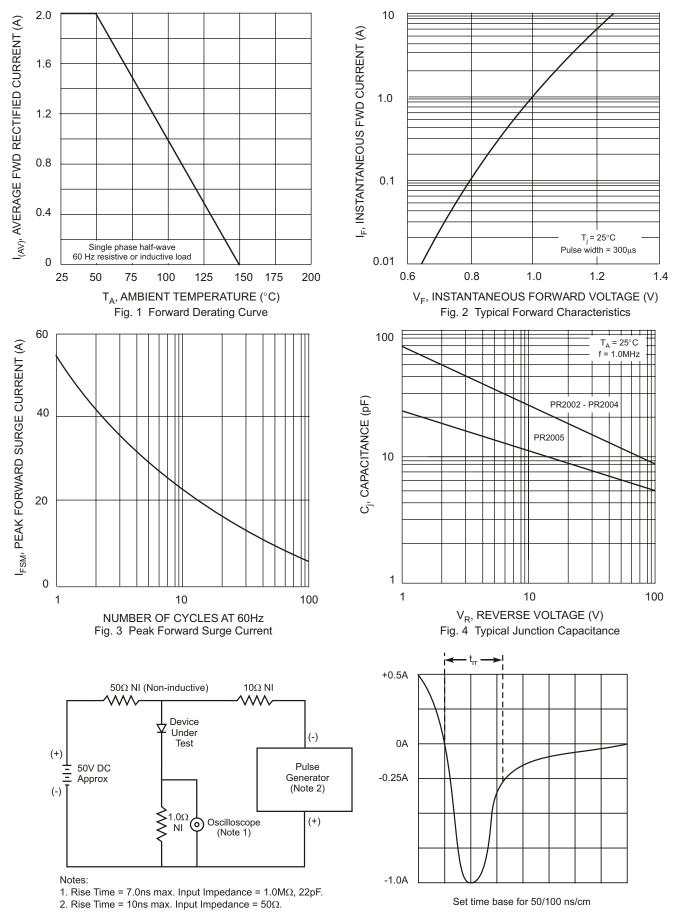


Fig. 5 Reverse Recovery Time Characteristic and Test Circuit